

# Low – Noise Preamplifier for SC diamond detectors

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# Summary

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- SC diamond as radiation detector
- Front–end electronics
- Experimental data
- Conclusions

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# SC Diamond as radiation detector

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Promising features:

- High radiation resistance
- Fast response time
- High band-gap ( 5.45 eV )



Very low leakage current

Low noise, even at high-temperature operation

# SC Diamond as radiation detector

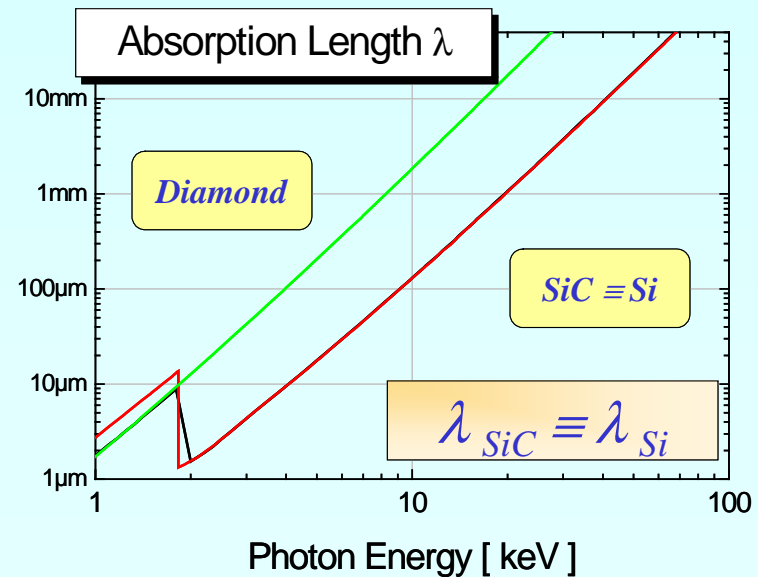
Spectroscopy with  $\alpha$  particle

Study for possible spectroscopy with X-rays



SC diamond could work at high temperature and in hostile environments with high resolution.

Absorption length short enough for photons  $< 8$  keV



# SC Diamond as radiation detector

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Energy resolution depends mainly on:

FANO: intrinsic line broadening

Charge Collection Efficiency

**ELECTRONIC NOISE:**

**Optimization of front-end electronics is  
necessary**

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# Front-end electronics

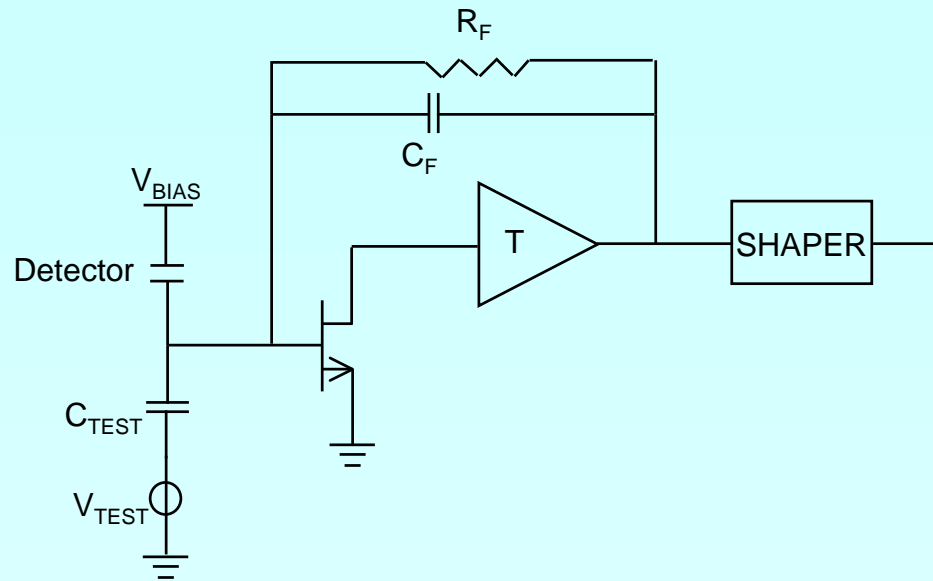
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In well-designed systems the noise arises practically from the detector and the front-end electronics sources (input FET, feedback resistor and polarization detector resistor, feedback and test capacitance dielectrics).

The classical solution is:  
Charge Sensitive Amplifier (CSP)  
DC coupled to detector



# Front-end electronics



Electronic Noise [coulomb rms]:

$$ENC^2 = \left( \alpha \frac{2kT}{g_m} C_{tot}^2 A_1 \right) \frac{1}{\tau_{sh}} + \left( 2\pi a_f C_{tot}^2 + \frac{b_f}{2\pi} \right) A_2 + \left( qI_L + \frac{2kT}{R_F} \right) A_3 \tau_{sh}$$

$C_{tot}$  sum of capacitances at preamp input;  $A_1$ ,  $A_2$  and  $A_3$  shaping constants;  $g_m$  transconductance of JFET;  $\alpha$  coeff. of channel thermal noise JFET;  $a_f$  coeff. of JFET 1/f series noise;  $b_f$  coeff. of dielectric parallel noise;  $I_L$  leakage current;  $R_F$  feedback resistance;  $\tau_{sh}$  shaping time

# Front-end electronics

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Good diamond detectors have  $I_L < 1 \text{ pA @ } 300 \text{ K}$

For the best resolution, noise of  $R_F$  must be negligible as compared to shot noise of  $I_L$ . So.....

$$R_F > 52 \text{ G}\Omega$$

Solution Proposed:

**FBFA**

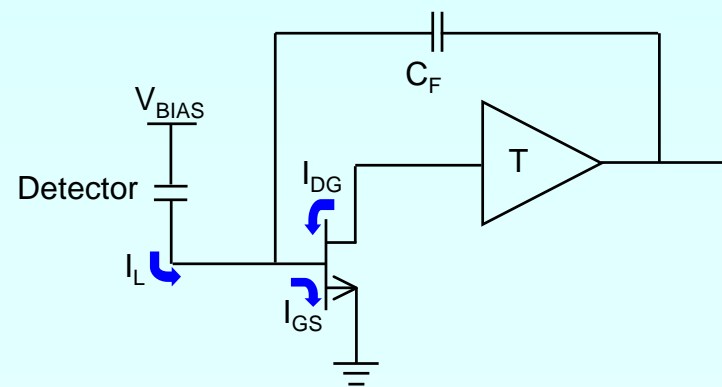
**(Forward Bias FET charge Amplifier)\***

\*G. Bertuccio, P. Rehak and D. Xi, Nucl. Instrum. Methods, vol. A326, pp. 71-76, 1993

# Front-end electronics

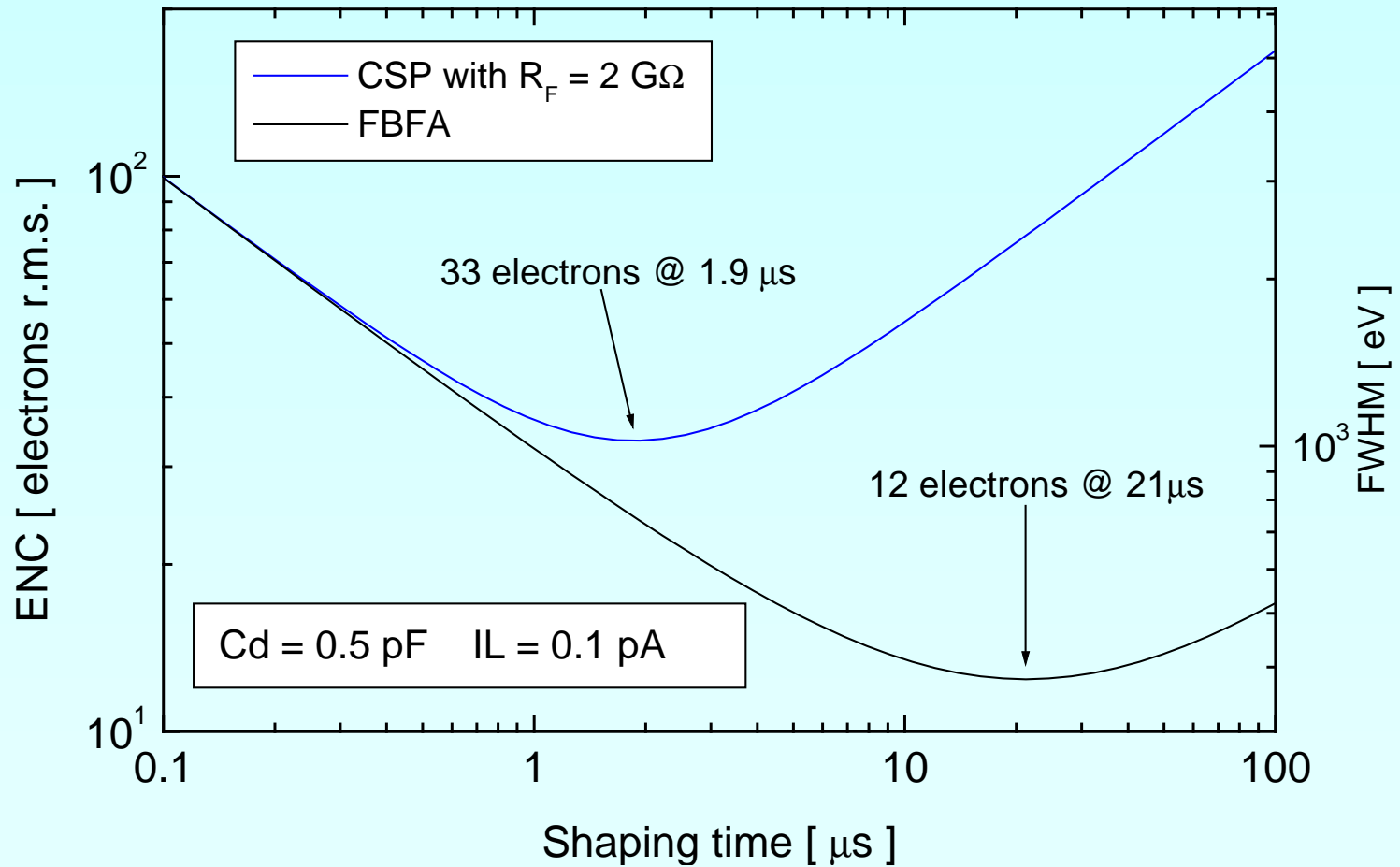
## FBFA: basic idea

Use the gate-to-channel junction of the input JFET as a path for the detector leakage current and for the discharge of the feedback capacitor



# Front-end electronics

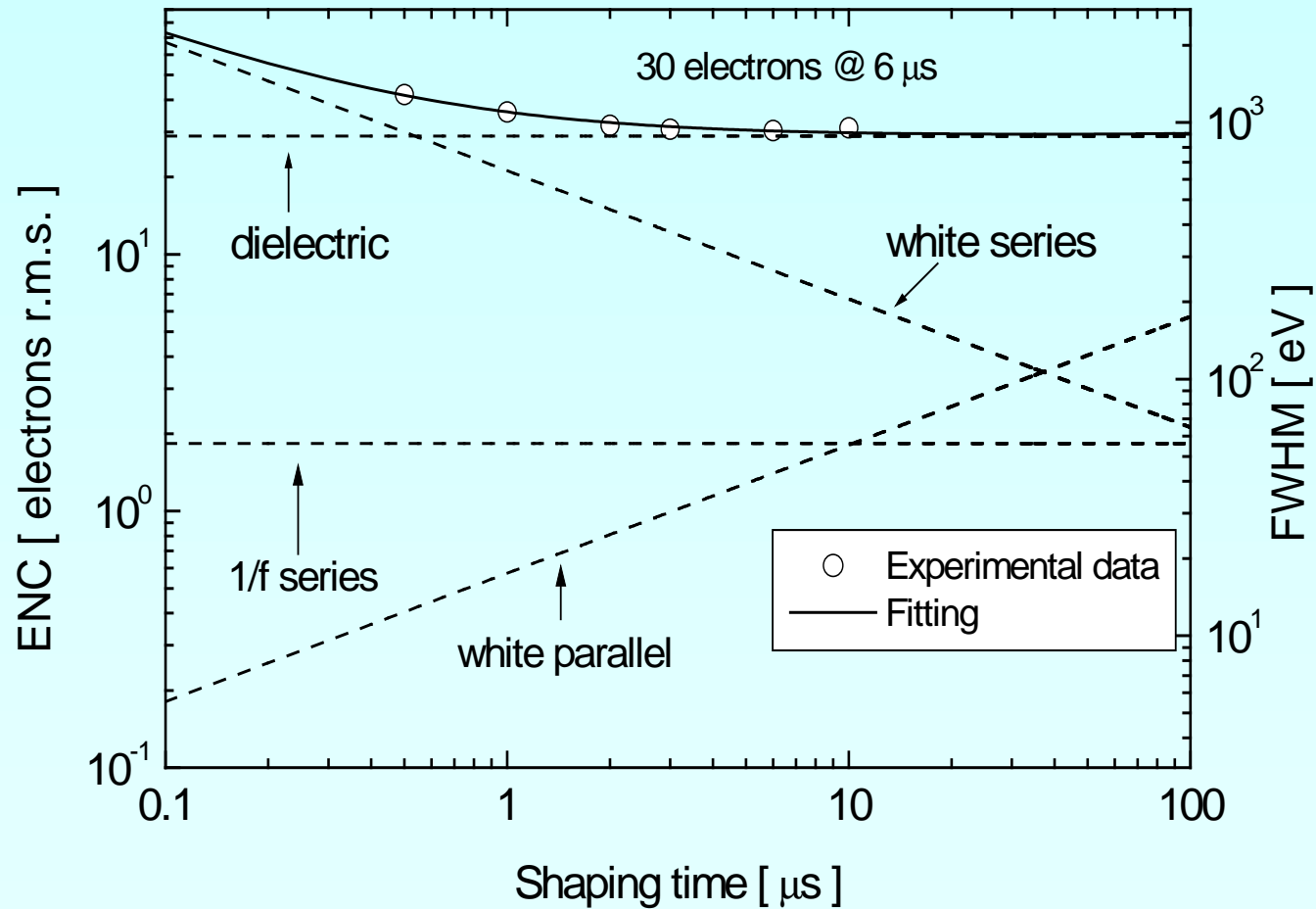
## Simulations



- SC diamond as radiation detector
- Front–end electronics
- **Experimental data**
- Conclusions

# Electronic Noise

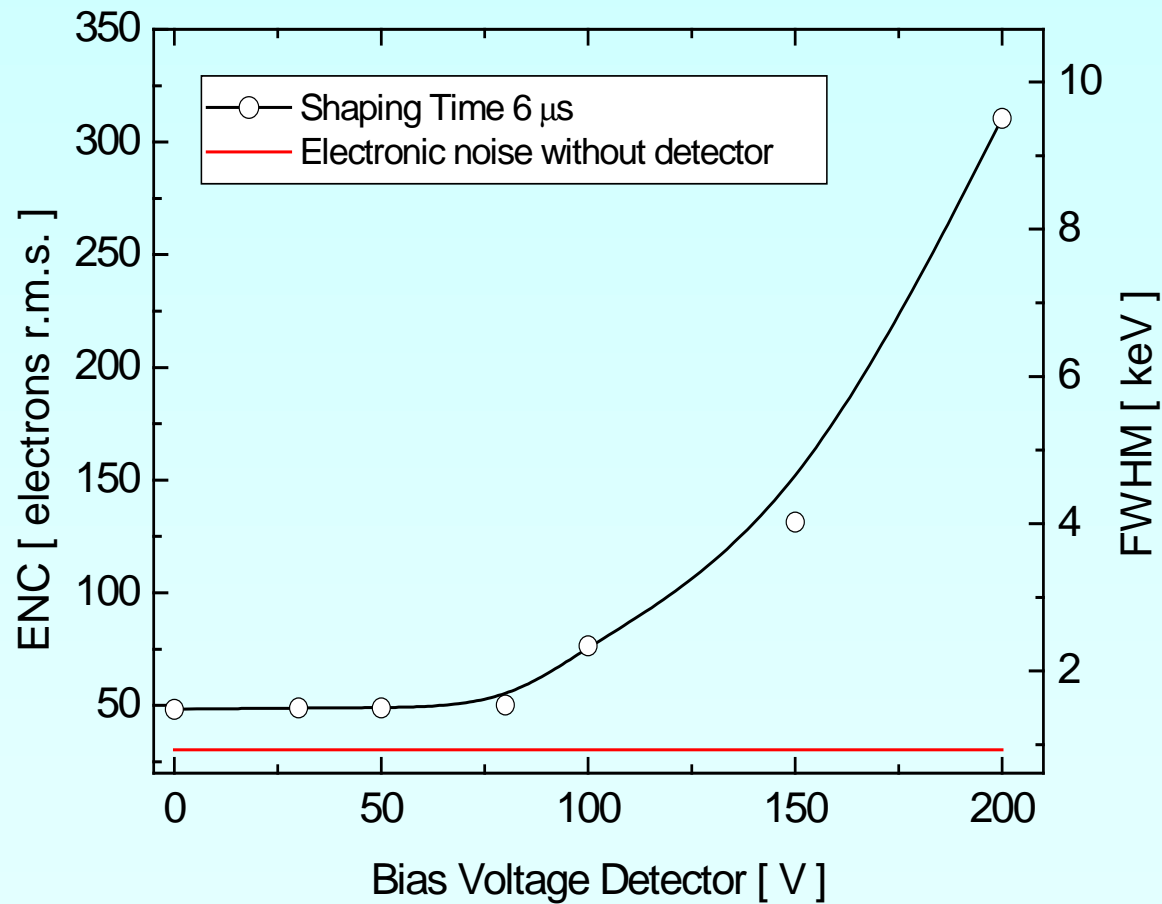
Diamond detector not connected



# Electronic Noise

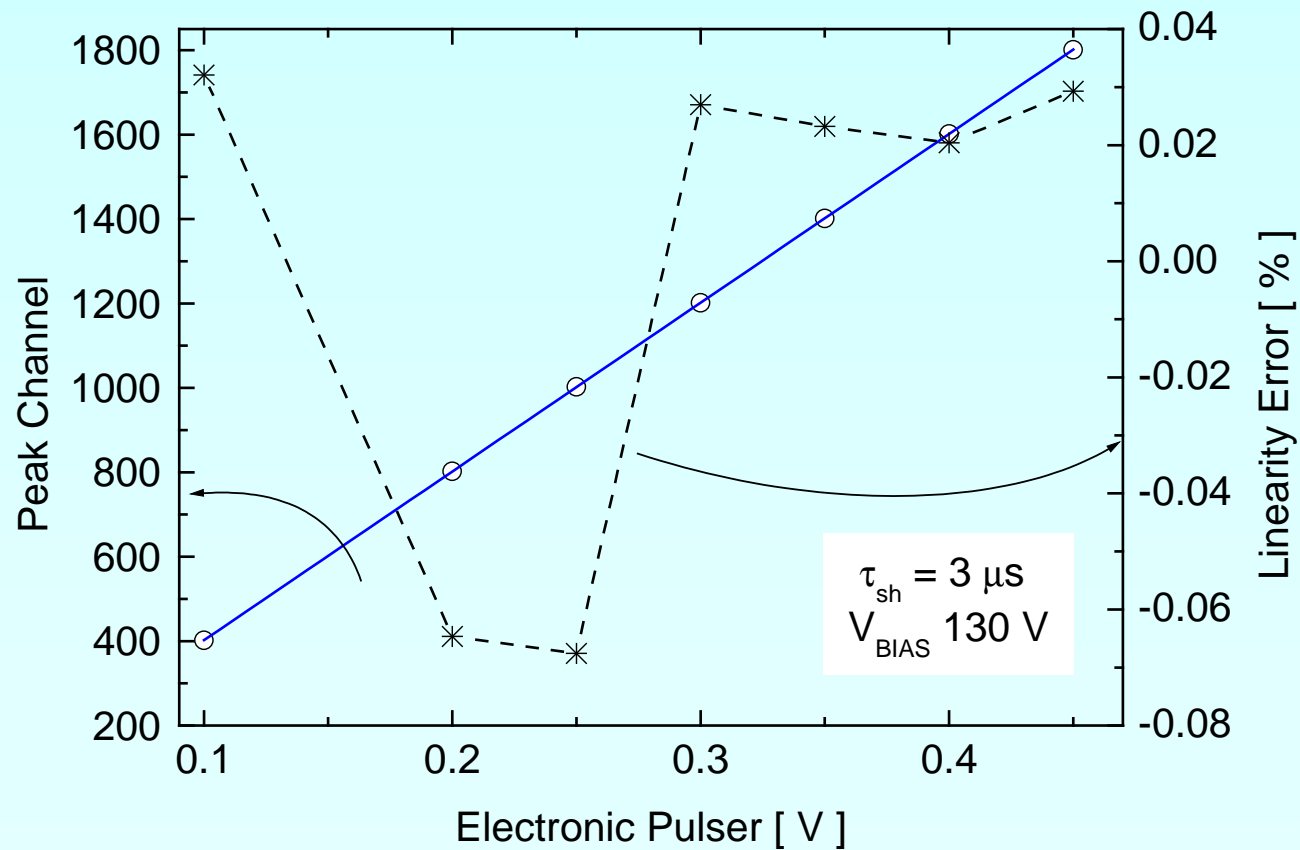
Diamond detector connected: #SC-E6-1

(thickness 440  $\mu\text{m}$ , high leakage current: 100 pA @ 100 V)



# Linearity

Electronic Chain for measurement: FBFA, Spectroscopy amplifier  
ORTEC 572, ADC ORTEC 919, Pulser Agilent 33220A

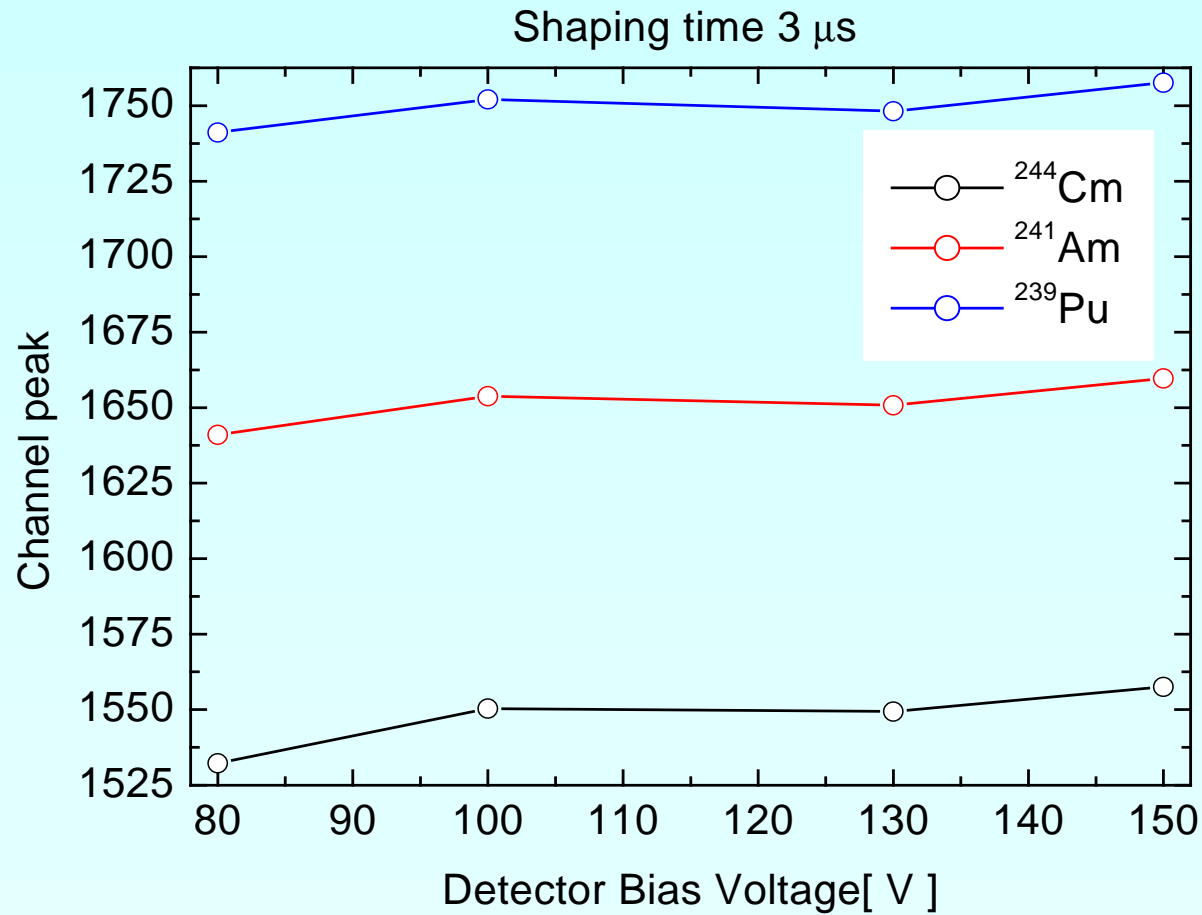


**Linearity Error**  
**< 0.1%**



# $\alpha$ -spectroscopy

Charge Collection Efficiency of used sample < 100 %



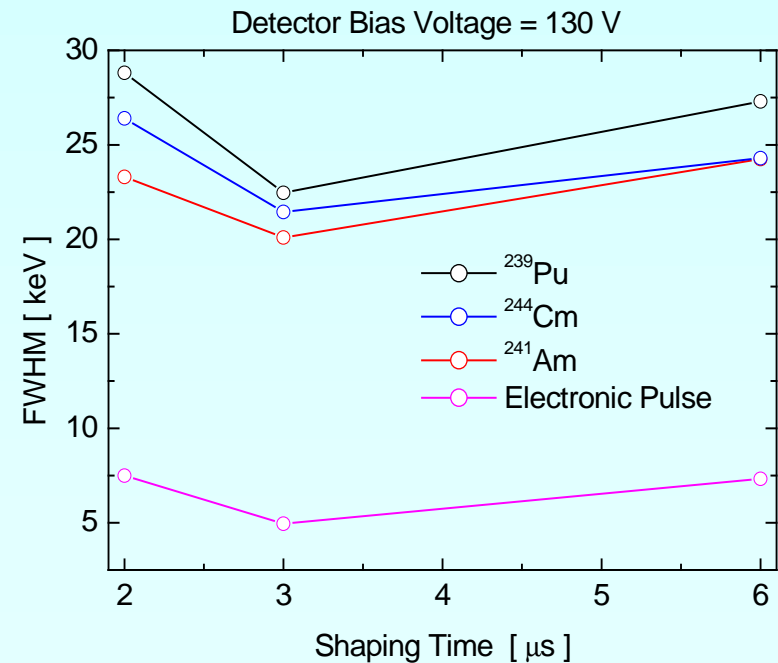
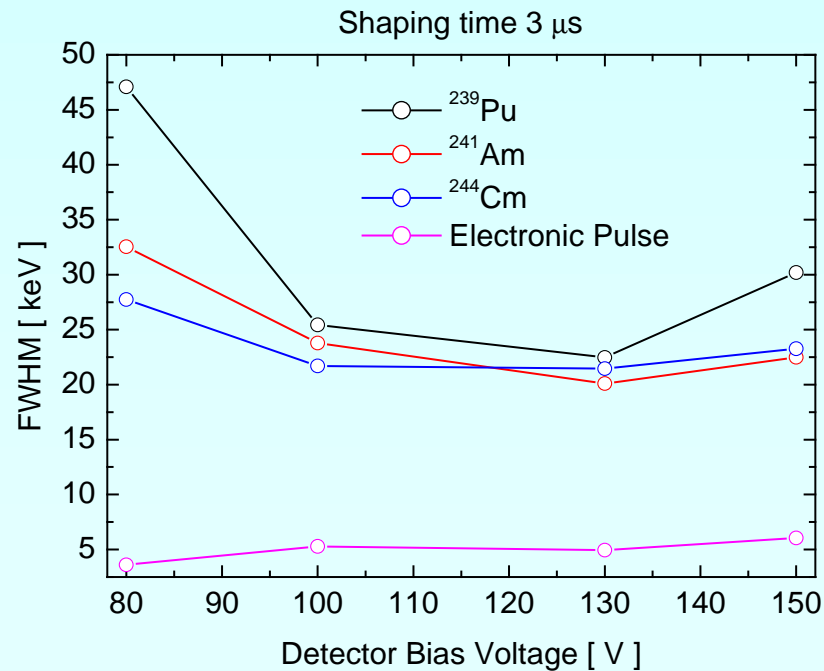
# $\alpha$ -spectroscopy

- for low electronic noise: low detector bias voltage
- for high CCE: high detector bias voltage

For the best resolution

$$V_{\text{BIAS}} = 130\text{V}$$

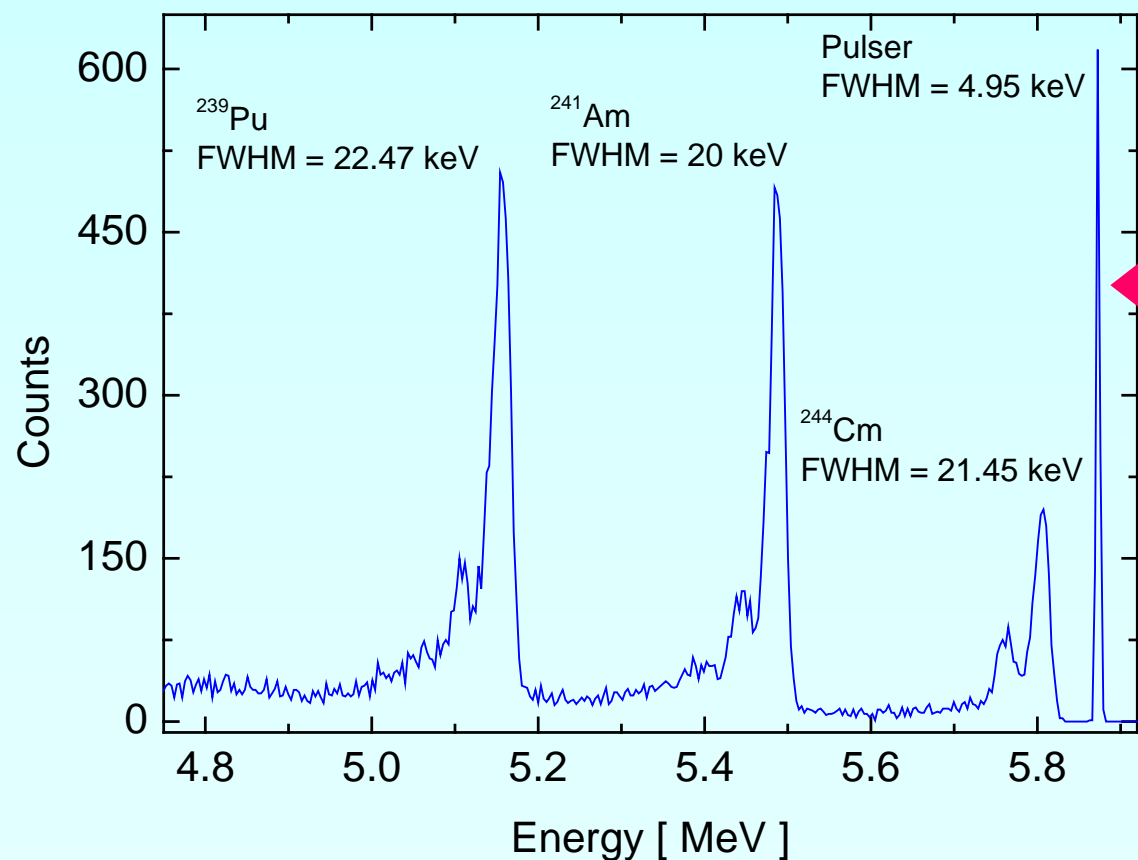
Optimum Shaping Time = 3  $\mu\text{s}$



# $\alpha$ -spectroscopy

Best spectroscopy resolution: 0.36 % @ 5.5 MeV

Bias Detector: 130 V - Shaping Time: 3  $\mu$ s

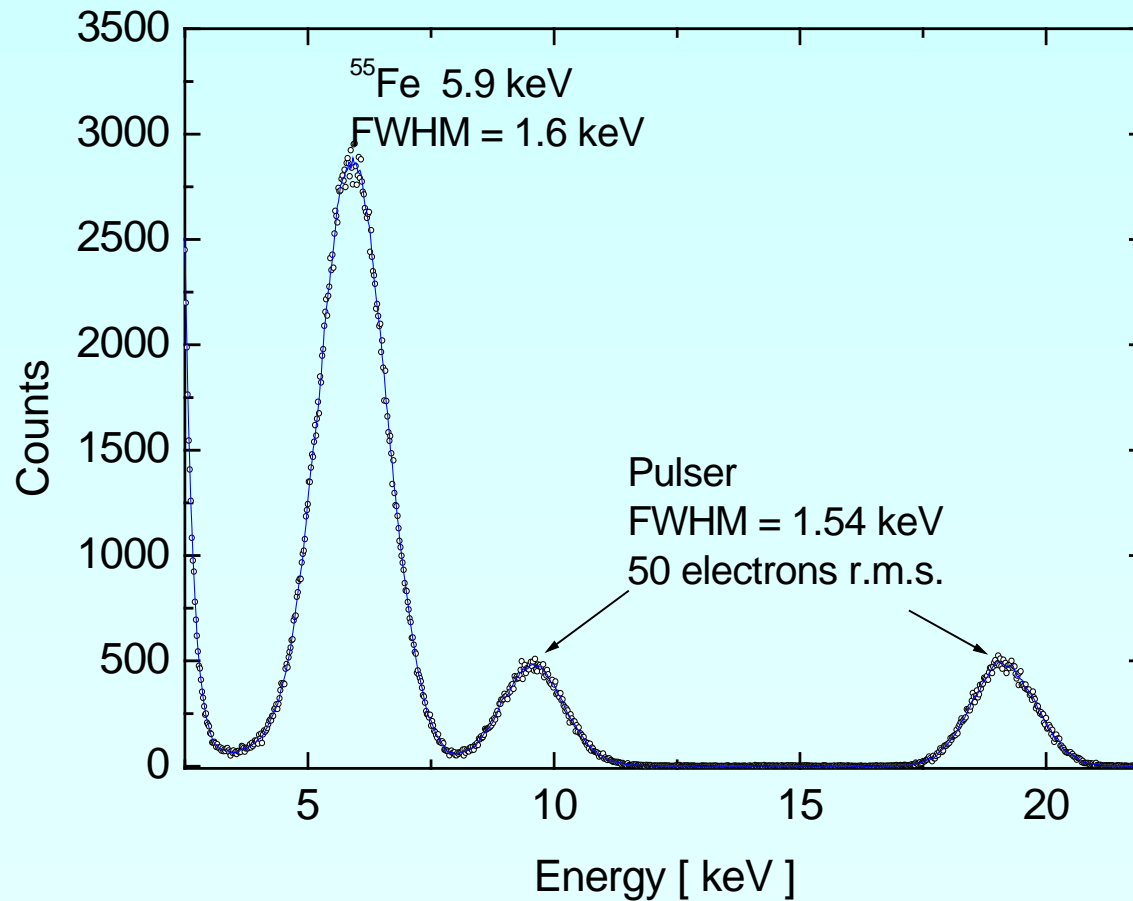


Pulser Line  
resolution  
0.08% !

# X-ray spectroscopy

## Best resolution

Bias Detector: 50 V - Shaping Time: 4  $\mu$ s



# Conclusions

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- The FBFA has an intrinsic resolution of 920 eV with SCD detectors.
- The high leakage current of the tested sample makes the electronic noise higher in our experimental measurements.
- For  $\alpha$  spectroscopy with our sample the resolution is limited above all by the Fano and the incomplete charge collection efficiency.
- Low energy X-ray spectroscopy is possible with very low leakage current.

# Future goals

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- FBFA with an electronic noise  $< 20 e$  (612 eV).
- With a very-low leakage current ( $< 1 \text{ pA}$ ) detector an improved resolution for  $\alpha$  and (above all) X-ray spectroscopy is possible.